

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Atty. Docket

BENOIT R. VEILLETTE

US 000295

Serial No.

jc943 U.S. PRO  
09/730659  
12/06/00

Filed: CONCURRENTLY

METHOD AND APPARATUS FOR CREATING AND TESTING A CHANNEL DECODER  
WITH BUILT-IN-SELF-TEST

Commissioner for Patents  
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.97

Sir:

Enclosed is a Form PTO-1449 and copies of documents listed thereon. These documents are considered to be relevant in that they have been:

X considered in drafting the specification of the above-referenced application;

X cited in the specification of the above-referenced application; or

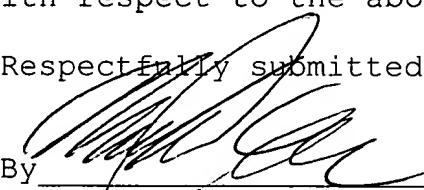
cited as an "X" or "Y" document in a foreign Patent Office search report on a foreign counterpart application a copy of which report is also enclosed.

I hereby certify that these documents were cited in said search report not more than three (3) months ago.

Please charge any fee under 1.17(p) for this Information Disclosure Statement to be considered, not exceeding \$240.00, to Account No. 14-1270.

If readily available, English-language counterparts have been substituted for foreign-language patent documents. This disclosure is not an admission that any of these documents is material to or even prior art with respect to the above-referenced application.

Respectfully submitted,

By   
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FORM PTO-1449	SERIAL NO.	CASE NO. US000295
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)	FILING DATE Concurrently	GROUP ART UNIT
	APPLICANT(S): BENOIT R. VEILLETTE	

1C843 U.S. PTO  
 09/730659  
 12/06/00



**REFERENCE DESIGNATION**      **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES      NO

EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)	
	A1	Article entitled "On-Chip Analog Signal Generation for Mixed-Signal Built-In Self-Test," <i>IEEE Journal of Solid-State Circuits</i> , Vol. 34, No. 3, March 1999, (Authors, Benoit Dufort and Gordon W. Roberts, Member, IEEE, Dated March 1999, pp. 318-330)
	A2	International Test Conference 95 article entitled, "A Built-In Self-Test Strategy for Wireless Communication Systems," Microelectronics And Computer Systems Laboratory, McGill University, Montréal, Quebec, Canada (Authors, Benoit R. Veillette, Gordon W. Roberts, Dated 95, 10 pp.)

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609;  
Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.